

ISO 17297:2025-05 (E)

Microbeam analysis - Focused ion beam application for TEM specimen preparation - Vocabulary

Contents		Page
Foreword		iv
Introduction		v
1	Scope	1
2	Normative references	1
3	Terms related to the physical basis of the FIB system	1
4	Terms related to FIB instrumentation	5
5	Terms related to TEM sample preparation by FIB	10
6	Terms related to scanning ion and scanning electron microscopy using the FIB-SEM system	11
Bibliography		14
Index		15